

# Stress determination by in-situ diffraction: laboratory, synchrotron, neutrons

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Instrumentation & Méthodes d'analyses pour étudier le couplage Mécanique/Diffusion/Oxydation  
05-06 June 2019

## Context

Stresses are everywhere !

sources of residual / internal stresses :

- ▶ fabrication process
- ▶ microstructures modification (thermal treatment - phase transformation)
- ▶ mechanical process (cutting, formability, ...)
- ▶ ageing
- ▶ oxidation
- ▶ ...

Stresses (residual or internal) can be beneficial or catastrophic !

## Context

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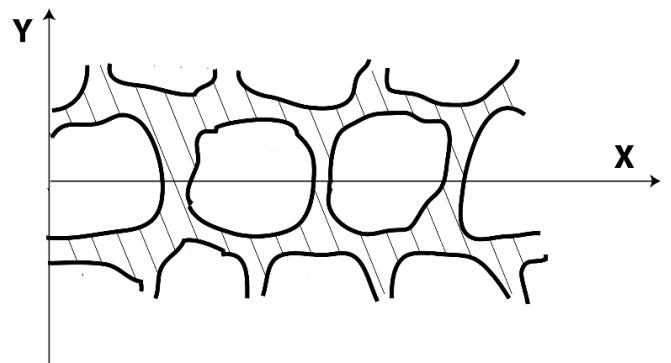
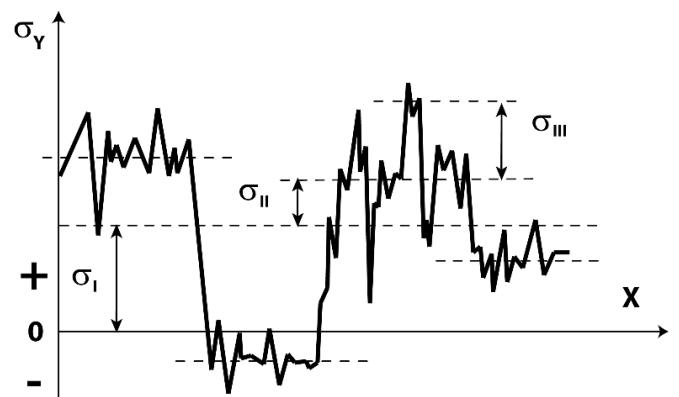
## Stress determination

Different levels of stress in materials

- ▶ sample scale
- ▶ grain scale
- ▶ intra granular scale

using diffraction methods

- ▶ phase scale
- ▶ laboratory scale
- ▶ large scale facilities : synchrotron sources and neutrons



## Overview

Stress determination by in-situ diffraction: laboratory, synchrotron, neutrons

Introduction

Laboratory

Common analysis  
Stress determination

on synchrotron

low energy - reflexion mode  
Laue method  
High energy diffraction

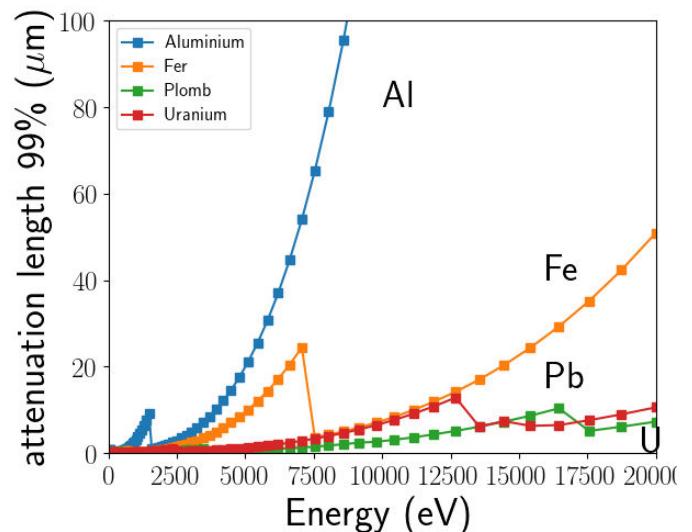
using neutrons

Conclusions

Acknowledgments

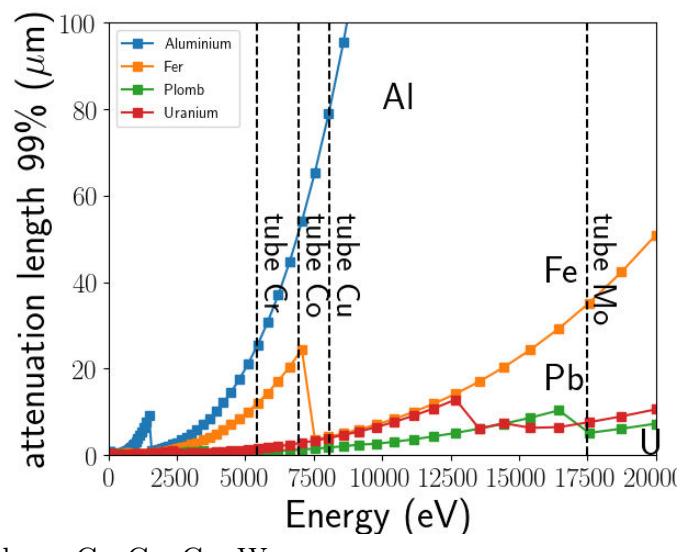
## Common analysis

in laboratory



tubes : Cr, Co, Cu, W, ...

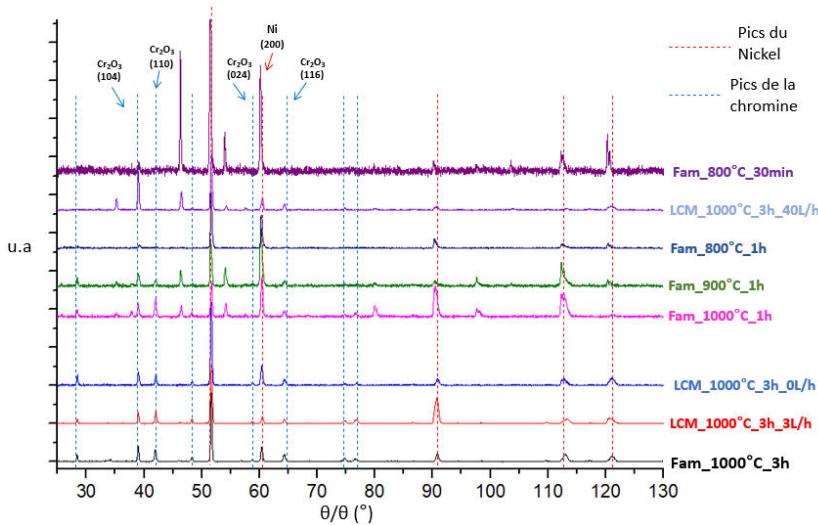
## Common analysis in laboratory



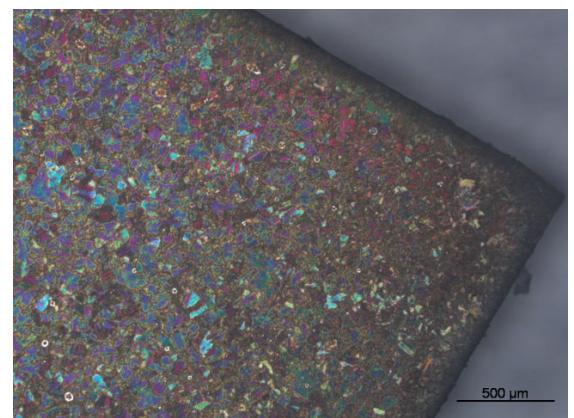
## Common analysis

in laboratory

1<sup>rst</sup> step : phase identification, ex : Ni38Cr.



→ X-ray are phase selective !



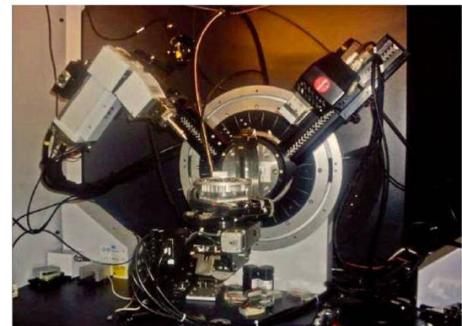
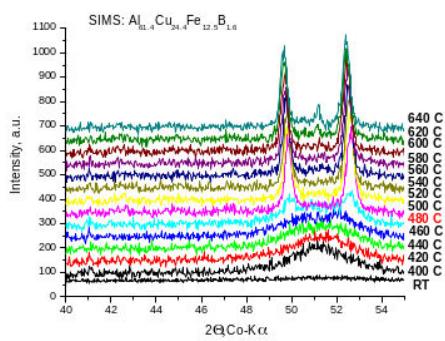
## Common analysis

in laboratory

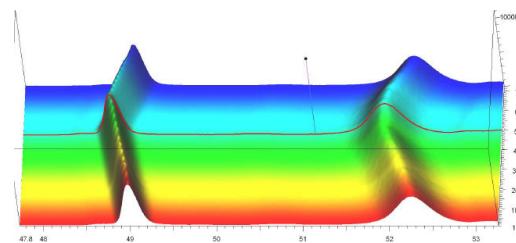
Temperature analysis :

- ▶ TTK450 : N2liq – 450 K
- ▶ HTK1200 : Tamb – 1200 ° C
- ▶ XRK900 : Tamb – 900 ° C
- ▶ DHS1100 : Tamb – 1100 ° C

PVD Characterization as a function of temperature

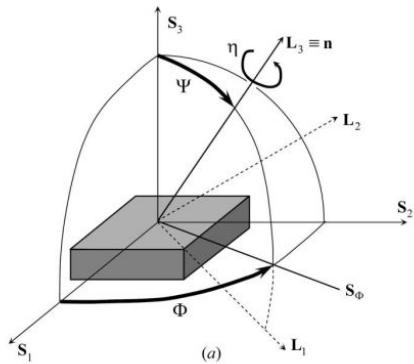


thermal expansion characterization of epitaxial layer

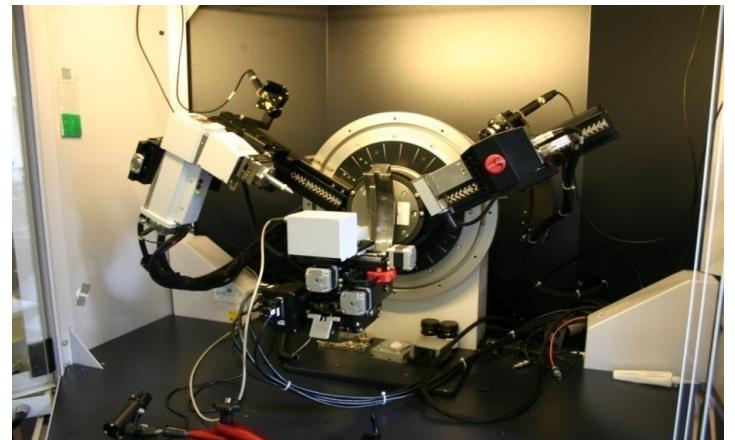


## Stress determination

in laboratory



Stress reference system in sample or laboratory space.



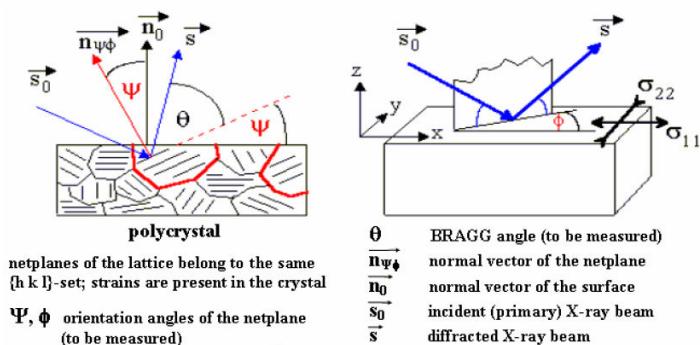
4 circles goniometer :  $\omega$ ,  $\theta$ ,  $\phi$ ,  $\chi$  (ou  $\psi$ ).

M. François J. Appl. Cryst. (2008). 41, 44–55

## Stress determination

Diffraction case

1<sup>er</sup> order (sample scale) -  $\sin^2\psi$  method



Hypotheses

- ▶ homogeneous and isotropic material
- ▶ elastic strain

$\sigma_\phi$  : Stress component along  $\phi$  direction

$d_0$  : reticular distance without stress

$d_{\phi,\psi}$  : reticular distance under stress

$\psi$  : declinaison angle

E: Young's modulus

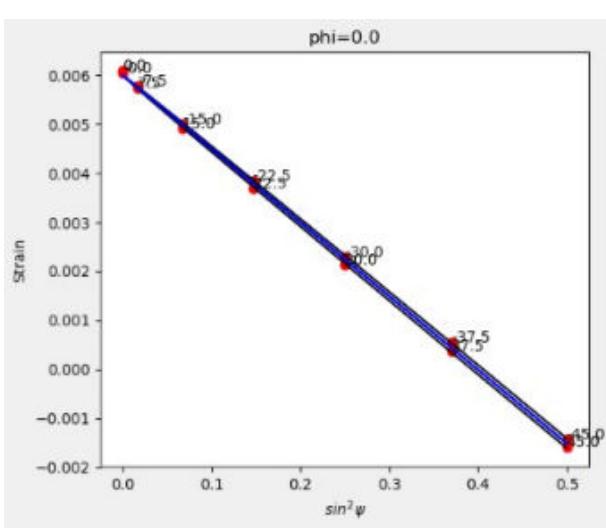
$\nu$  : Poisson's ratio

Strain in along ( $\phi, \psi$ ) direction is related to the elements  $\sigma_{ij}$  of stress tensor using:

$$\epsilon_{\phi\psi} = \frac{1}{2} S_2 [(\sigma_\phi - \sigma_{33}) \sin^2\psi + \sigma_{33} + (\sigma_{13}\cos\phi + \sigma_{23}\sin\phi)\sin2\psi] + S_1(\sigma_{11} + \sigma_{22} + \sigma_{33}) \quad (1)$$

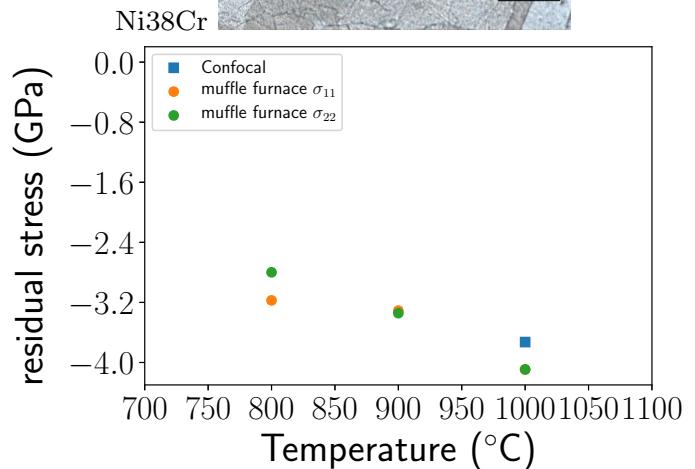
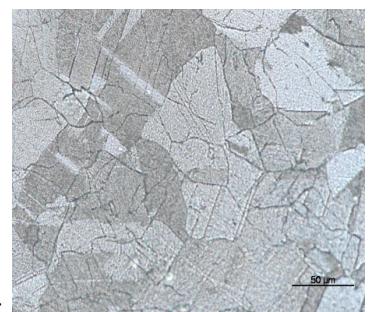
## Stress determination

in laboratory



residual stress :  $-3977 \pm 50$  MPa

X-Light software  
(<https://github.com/sangpham171/X-Light>)



## Stress determination

in laboratory

Stresses determination using laboratory devices.

- ▶ residual stresses determination
- ▶ different kinds of characterization methods
- ▶ flexible
- ▶ time consuming
- ▶ limited energy range (tubes)
- ▶ reflection mode for bulk samples
- ▶ limited penetration depth (normal stress undetermined)

## Stress determination

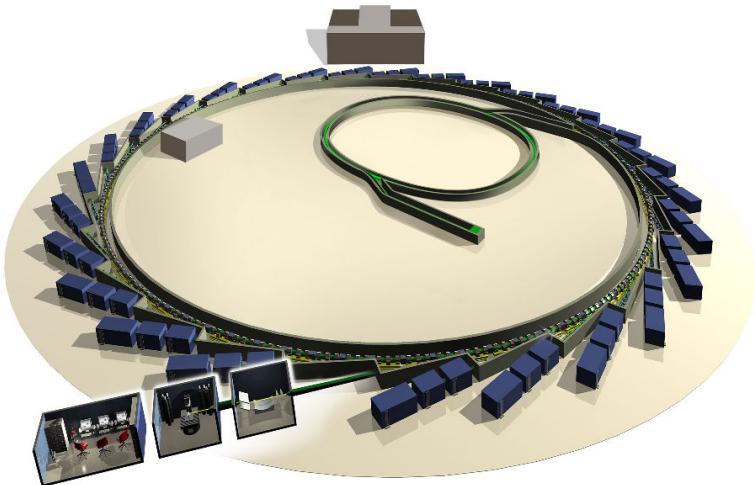
in laboratory / on synchrotron(s)

Stresses determination using laboratory or **synchrotron** devices.

- ▶ residual stresses determination + **internal stresses**
- ▶ different kinds of characterization methods + **coupled techniques**
- ▶ **flexible**
- ▶ time consuming → experiments planned over 1 year + lot of data and data analysis
- ▶ limited energy range (tubes) **almost no limit**
- ▶ reflection mode for bulk samples **almost no limit**
- ▶ limited penetration depth (normal stress undetermined) **almost no limit and full tensor determination**

## Stress determination

in laboratory / on synchrotron(s)



Schematic of Diamond Light Source, showing the components that make up the synchrotron.

→ more than 50 light sources worldwide (synchrotron, XFEL) [lightsources.org](http://lightsources.org)

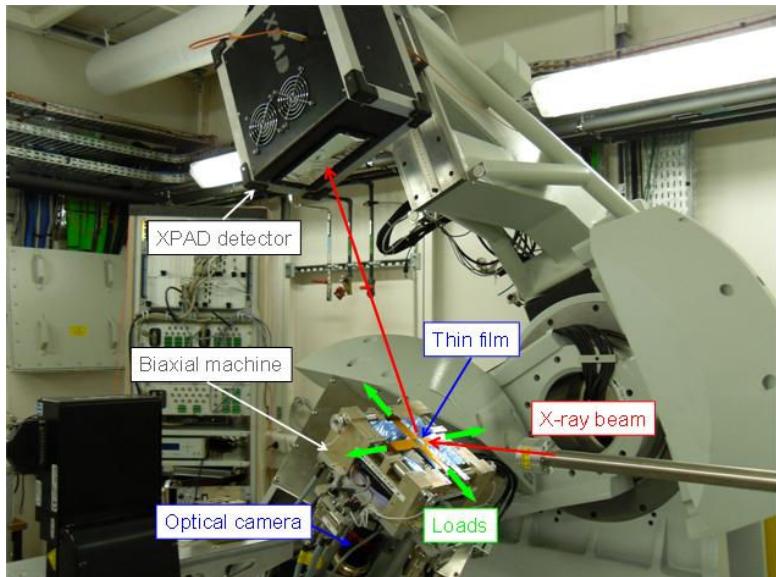
Energy : 1meV to 750 keV — beam size : 50nm – cm



## Internal stress determination

on synchrotron(s)

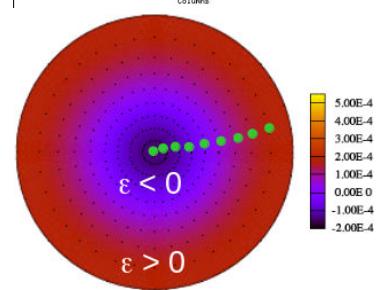
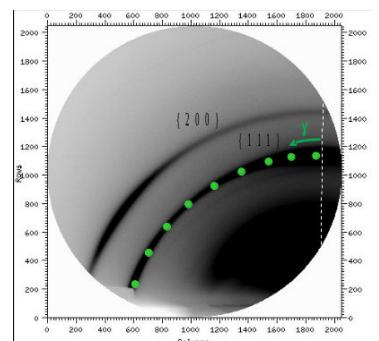
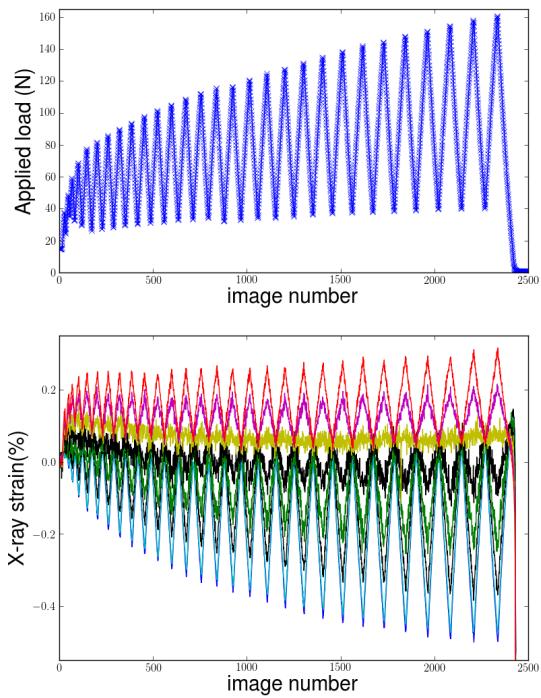
Experimental set-up at DiffAbs beamline at SOLEIL.



In-situ biaxial tensile test combined with X-rays diffraction and image correlation techniques.

XRD lattice strains  
DIC true strains

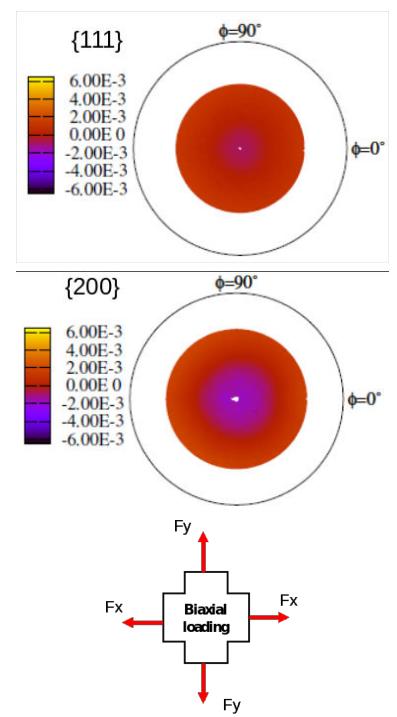
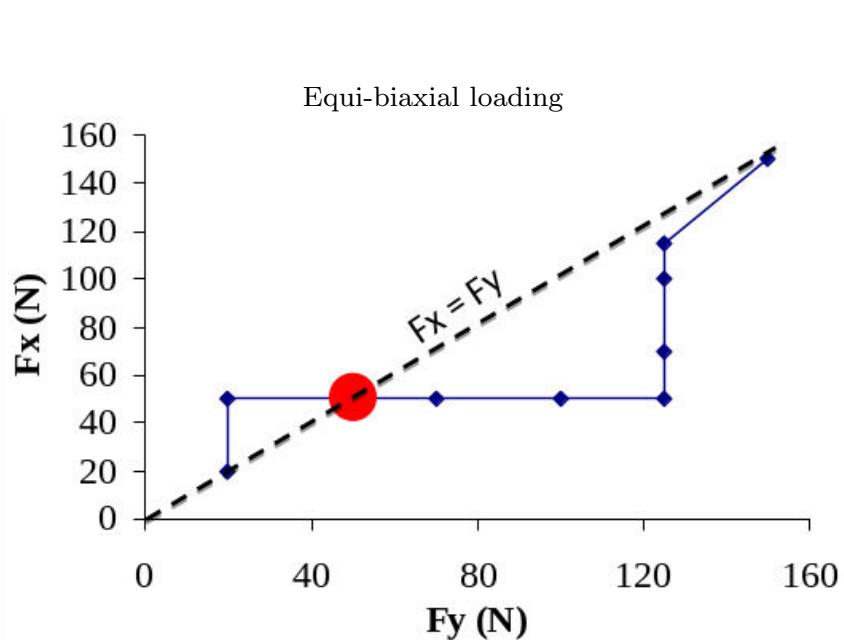
## Internal stress determination on synchrotron(s)



{111} Strain Pole Figure

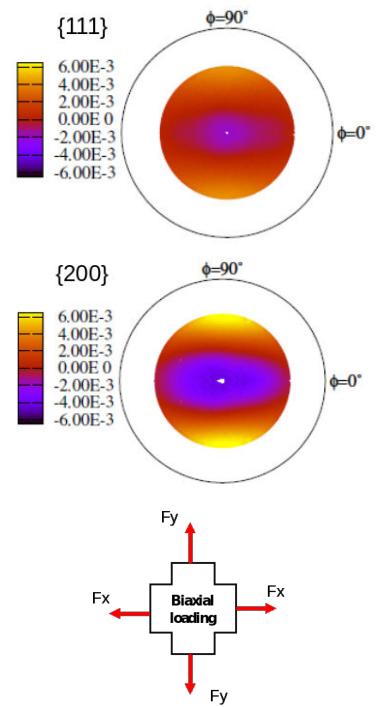
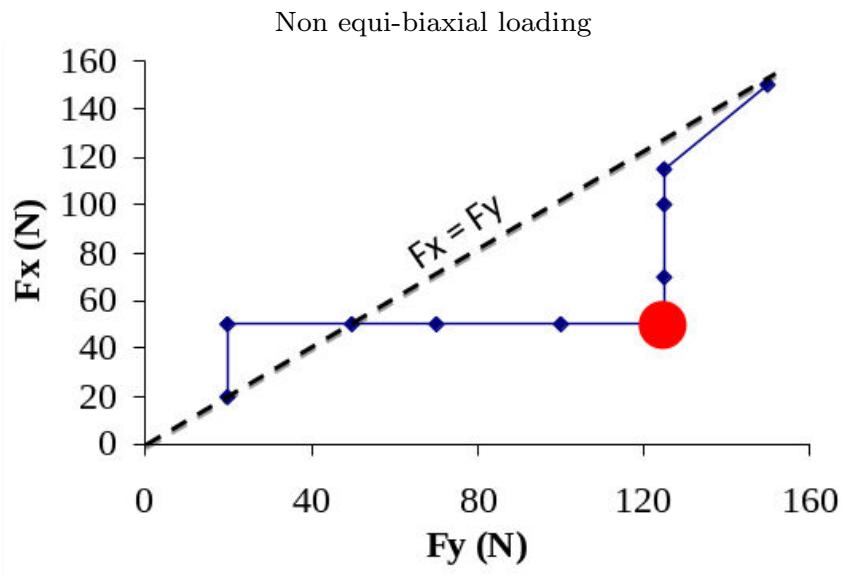
## Internal stress determination

on synchrotron(s)



## Internal stress determination

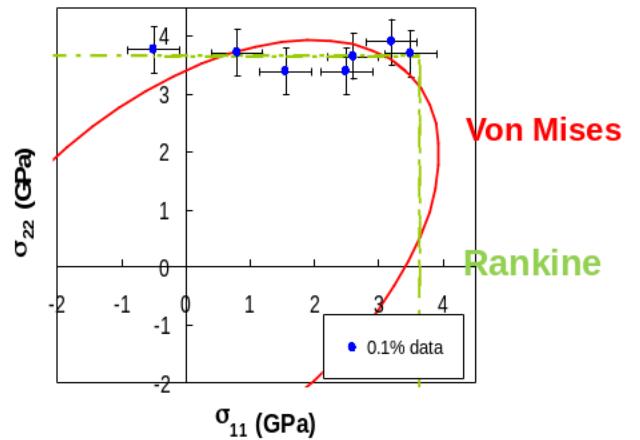
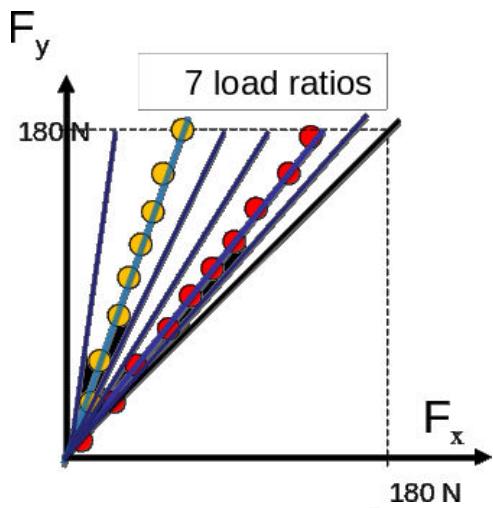
on synchrotron(s)



## Internal stress determination

on synchrotron(s)

In situ biaxial tensile test combining XRD and DIC  
Mechanical behaviour of thin film:  
Yield surface: Brittle behaviour



Djaziri et al., Acta Mater. 61 2013 // Renault et al., ICMCTF May, 2013

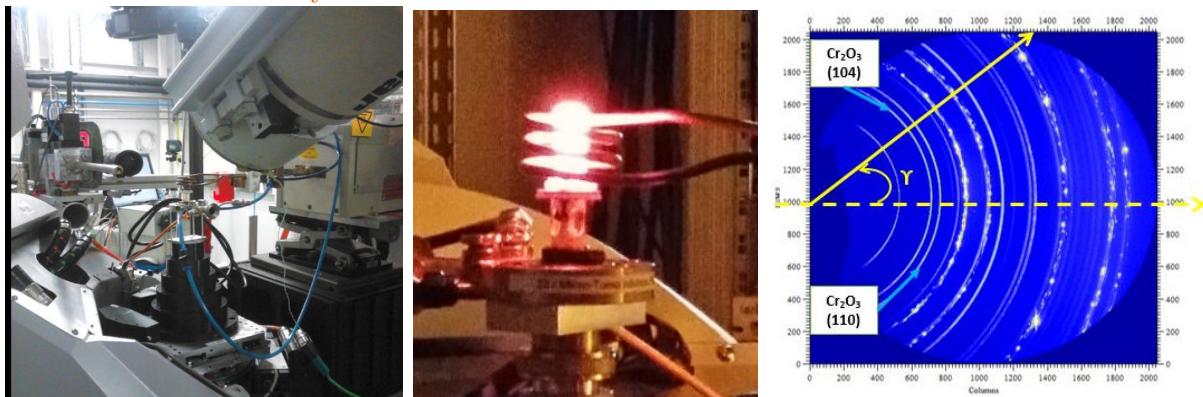
## Internal stress determination

on synchrotron(s)

Ni-30Cr (non-textured alloy): nickel containing chromium alloy

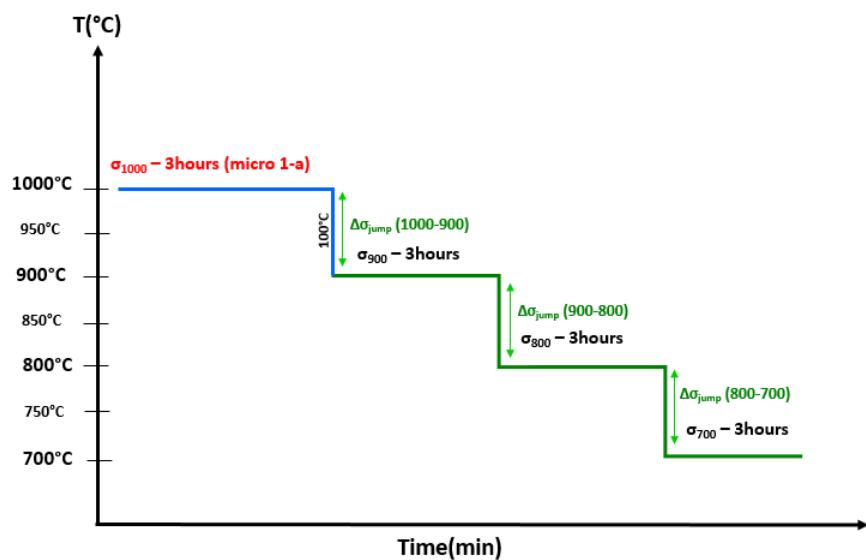
	% Ni	% Cr	% Si	% Mn	C	P	S
Ni-30Cr	69.65	30.22	inf 0.01	0.01	230 ppm	30 ppm	40 ppm

Synchrotron radiation and in situ measurements

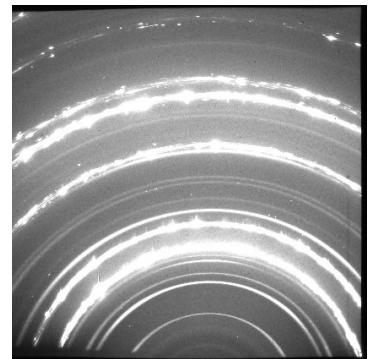


Beamline BM02, ESRF Grenoble

## Internal stress determination on synchrotron(s)



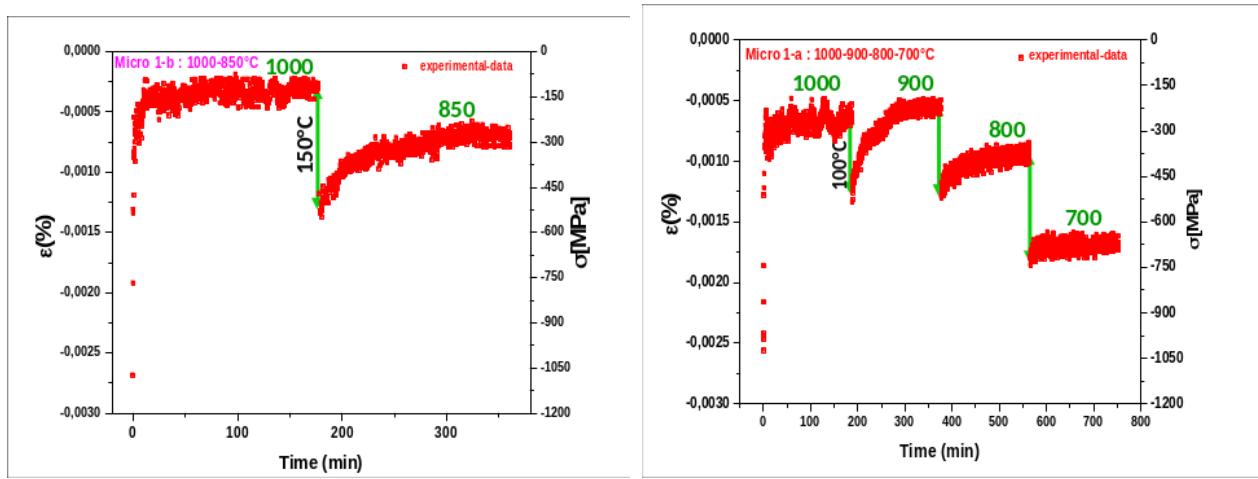
During thermal treatment :  
continuous recording of 2D  
images  
1 test == 3700 images



Rakotovao F. PhD thesis, Université de la Rochelle, 2016

## Internal stress determination

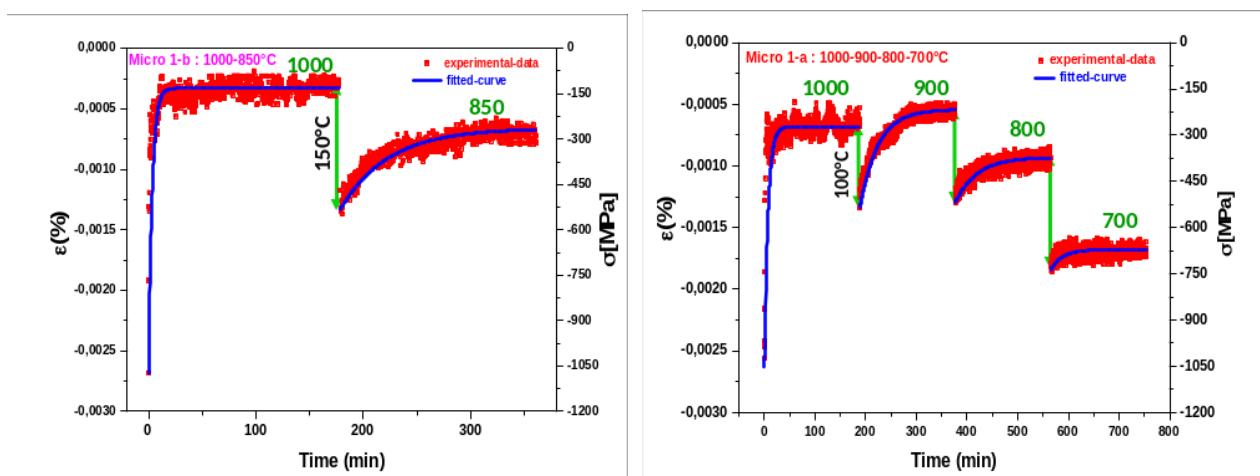
on synchrotron(s)



Rakotovao F. PhD thesis, Université de la Rochelle, 2016

## Internal stress determination

on synchrotron(s)

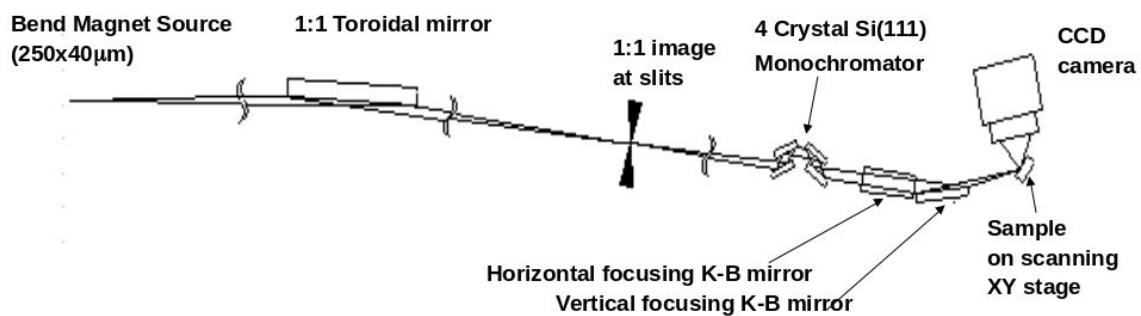


With  $n=1$ , fitted curves well describe experimental behaviour  
→ evidence of diffusion-creep relaxation in  $\text{Cr}_2\text{O}_3$

Rakotovao F. PhD thesis, Université de la Rochelle, 2016

## Internal stress determination

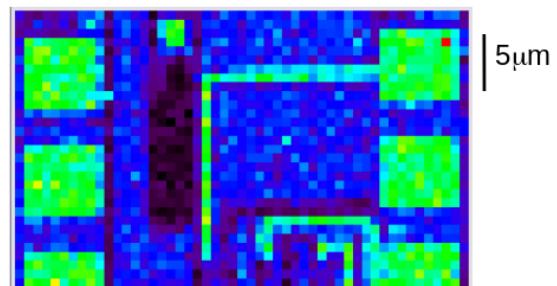
sur synchrotron(s) : Laue method



Beam size on sample:  $0.8 \times 0.8 \mu\text{m}^2$

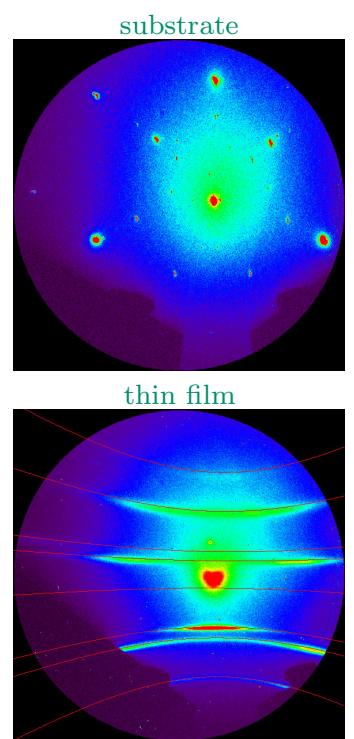
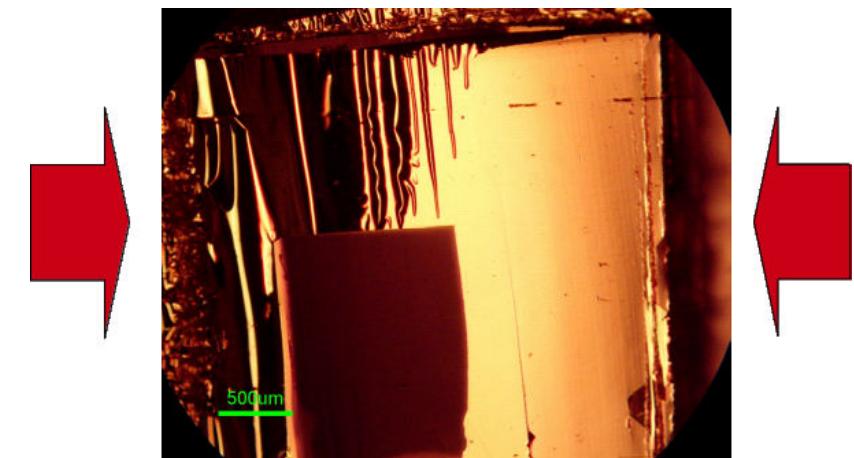
Photon energy range : 5-25 keV (pink beam)  
monochromatic beam – method available

fluorescence



## Internal stress determination

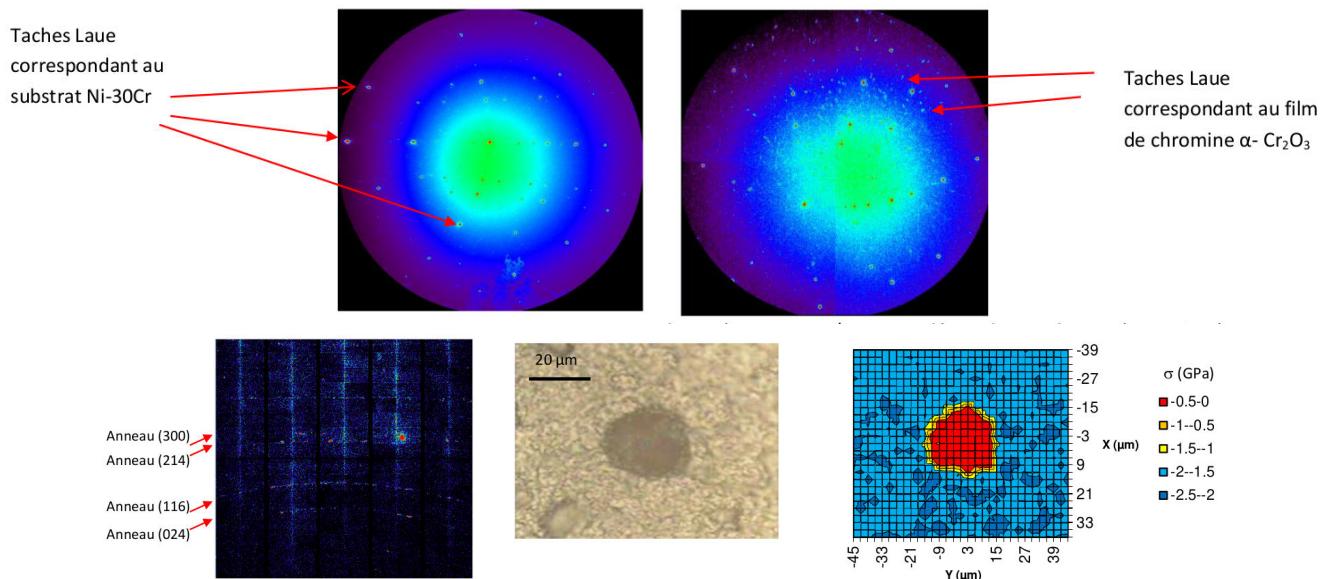
sur synchrotron(s): Laue method



Compression of thin film deposited on monocrystalline substrate  
combining Laue microdiffraction / monochromatic microdiffraction

## Internal stress determination

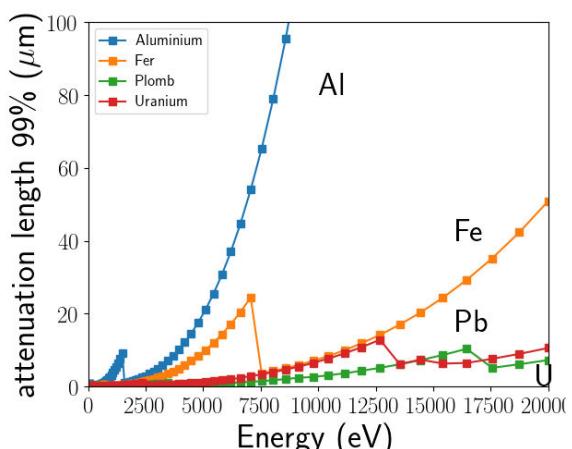
sur synchrotron(s): Laue method



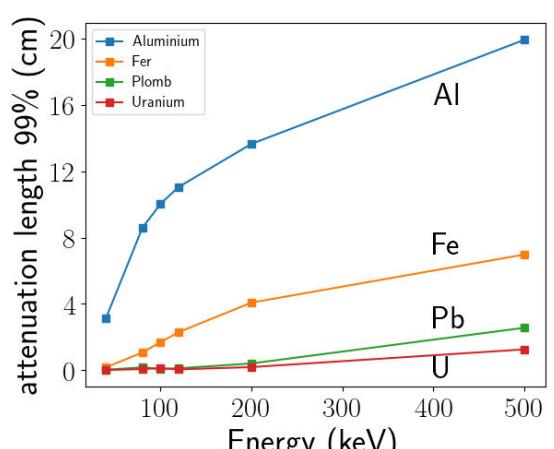
Guérain M. PhD thesis, Université de la Rochelle, 2012

## Internal stress determination

on synchrotron(s) : high energy



Laboratory / low energy beamlines

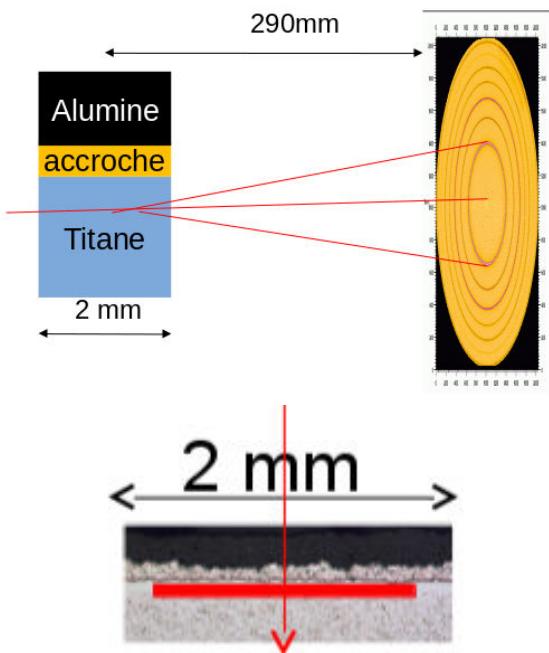


High energy beamlines

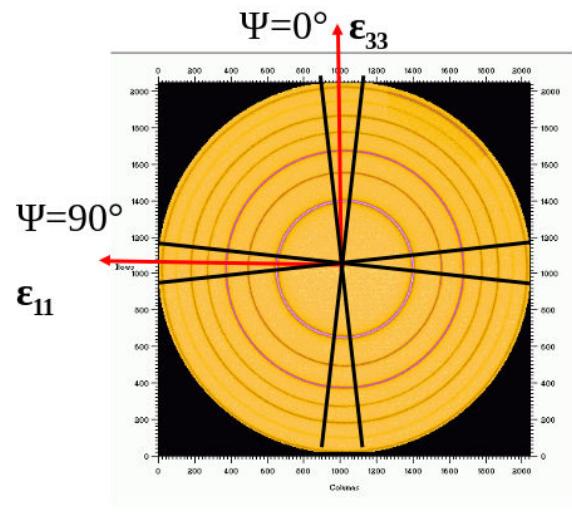
## Internal stress determination

on synchrotron(s) : high energy

ID11 : Transmission, E= 80 keV



Beam size: h: 5  $\mu\text{m}$  v: 300  $\mu\text{m}$



Sample rotation ( $0^\circ$ ,  $90^\circ$ )

## Internal stress determination

on synchrotron(s) : high energy

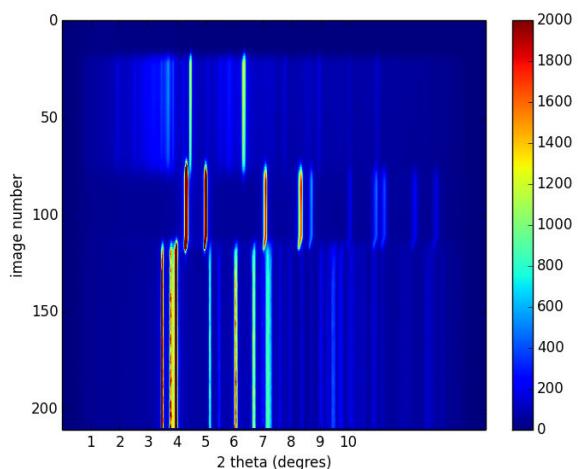
- ▶ multilayer material
- ▶ multiphase material

Stress determination in each phase  
Stress determination along each direction  
→ Full tensor determination along depth

One complete analysis:

- ▶ 100 2D images (scan over 500 $\mu\text{m}$ ) for each profile
    - 15 for Alumina
    - 10 for hanging layer
    - 80 for Titanium
  - ▶ 2 directions:  $\phi=0^\circ$  and  $90^\circ$
  - ▶ 4 phases : 1 in alumina, 1 in hanging layer and 2 in titanium alloys
- **130000 peaks to analyze**

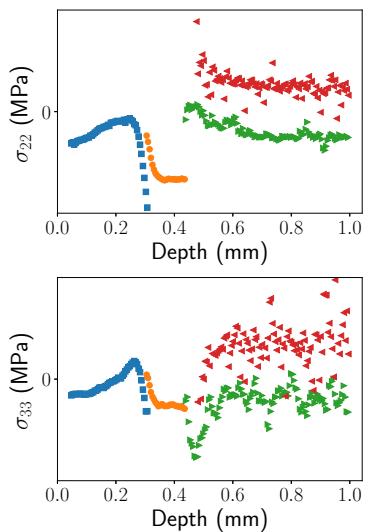
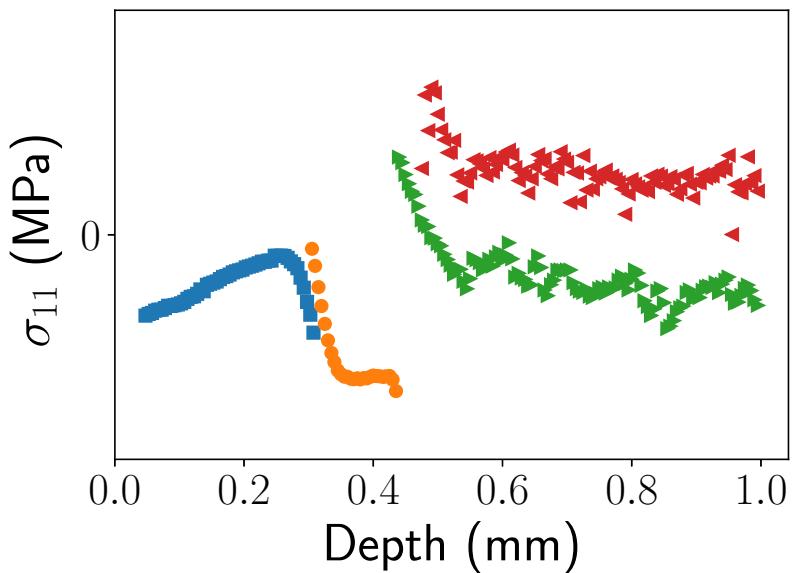
Phase mapping along depth



## Internal stress determination

on synchrotron(s) : high energy

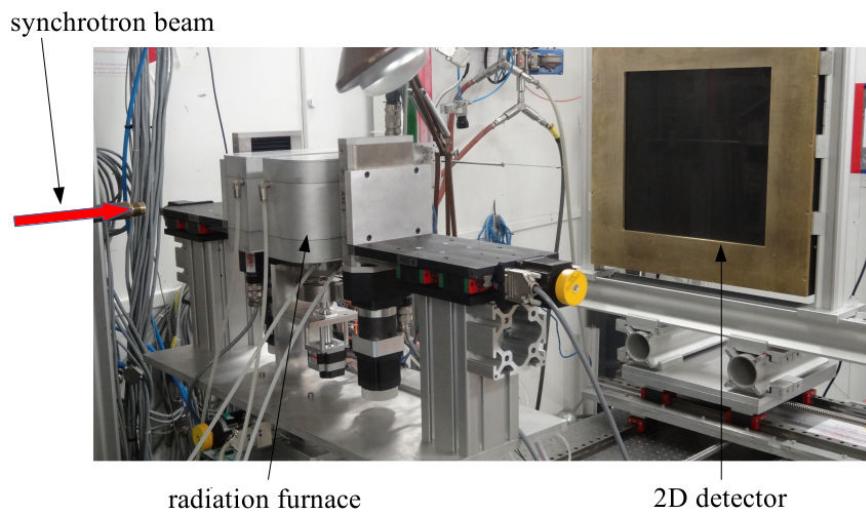
residual stress profils at a function of depth:



## Internal stress determination

on synchrotron(s) : high energy

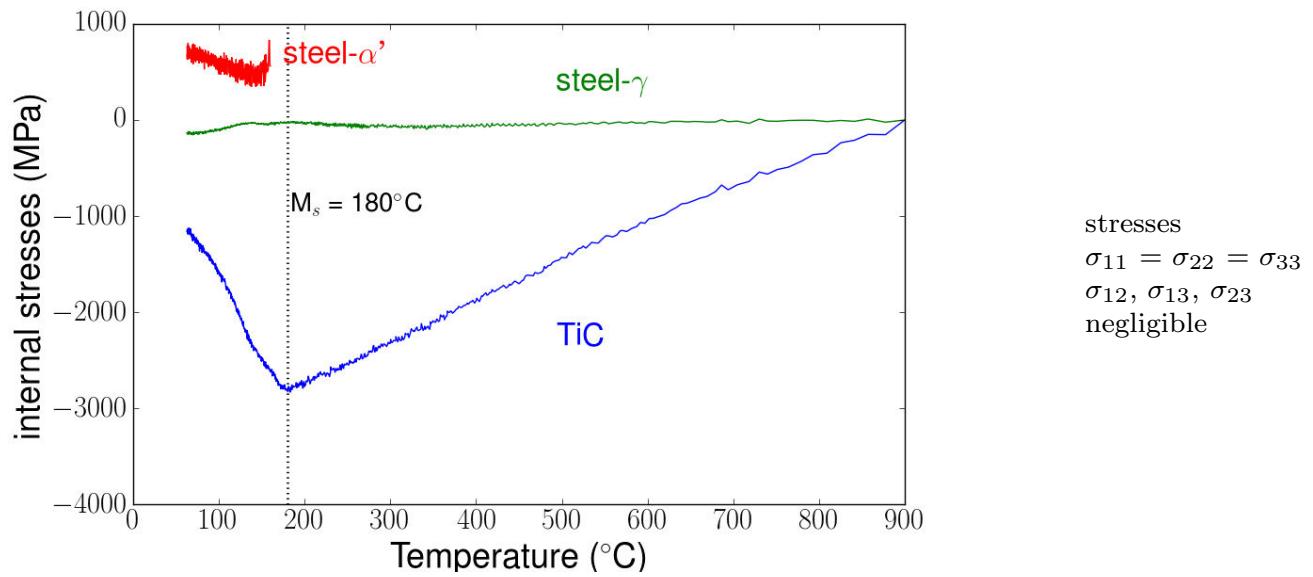
- ▶ Radiation furnace
- ▶ Welded thermocouple
- ▶ Argon atmosphere
- ▶ Sample rotation
- ▶ ID15B (ESRF)
- ▶ High energy beam ( 87 keV)
- ▶ Transmission geometry
- ▶ 2D detector
- ▶ Acquisition rate : 10 frames / s
- ▶ Beam size : 400 x 400  $\mu\text{m}^2$



## Internal stress determination

on synchrotron(s) : high energy

Mean stresses in MMC versus temperature



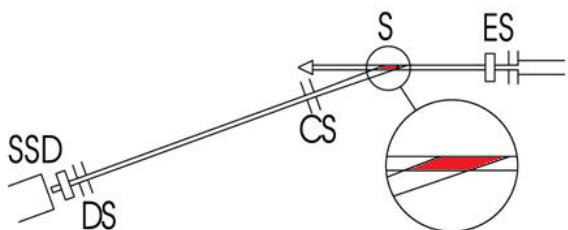
Geandier et al, Materials 2018, 11, 1415; doi:10.3390/ma11081415

## Internal stress determination

on synchrotron(s) : high energy

### Energy dispersive setup

- ▶ fixed angle
- ▶ white beam: 50 - 300 keV
- ▶ 3D scans
- ▶ Energy dispersive detectors



## Internal stress determination

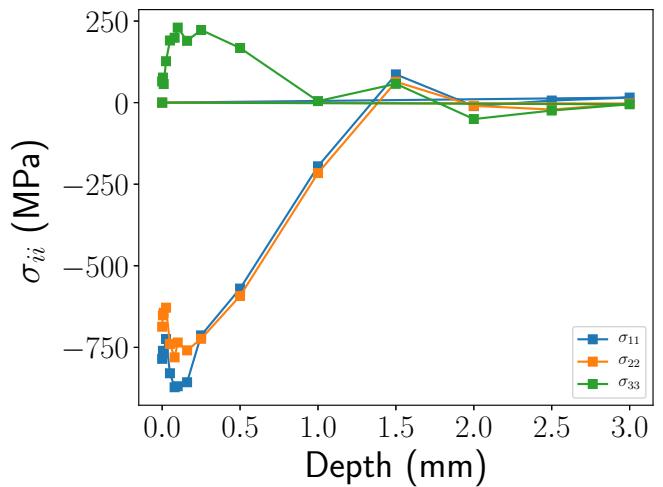
on synchrotron(s) : high energy

### Energy dispersive setup

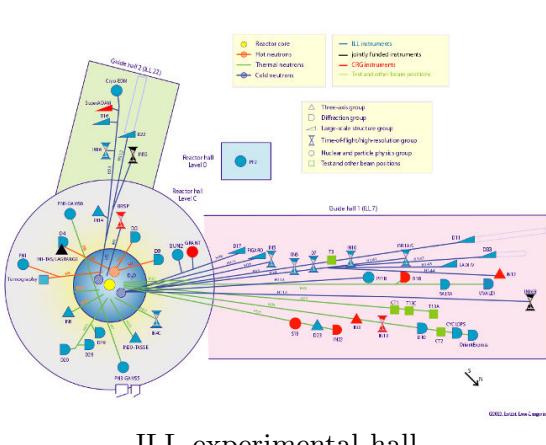
GFAC samples

- ▶ Full stress tensor determination
- ▶ shot-peened samples
- ▶ mono phase sample : inconel
- ▶ no material removal

→ good agreement between synchrotron and laboratory (with material removal) measurements



## Stress determination with neutrons



→ 43 neutron sources worldwide [neutronsources.org](http://neutronsources.org)



## Stress determination

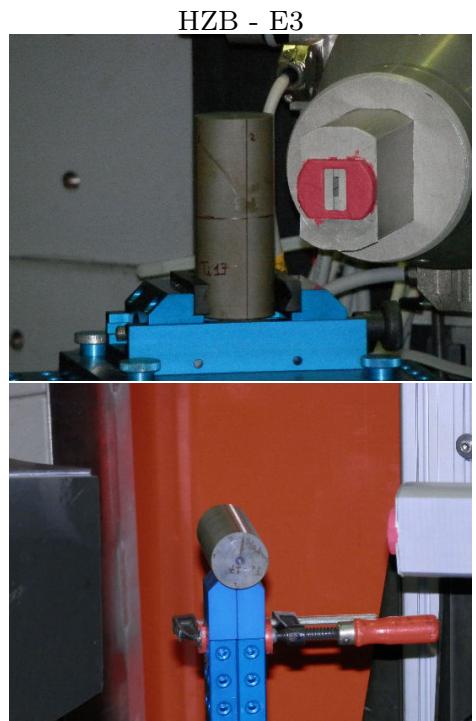
with neutrons

- ▶ large penetration depth
- ▶ large gauge volume
- ▶ heavy samples
- ▶ full stress tensor

Example:

Titanium alloys

Cylinder (h 200mm, 40mm diameter)

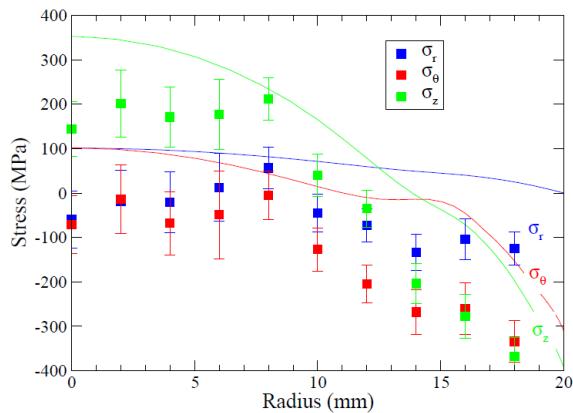


## Residual stress determination

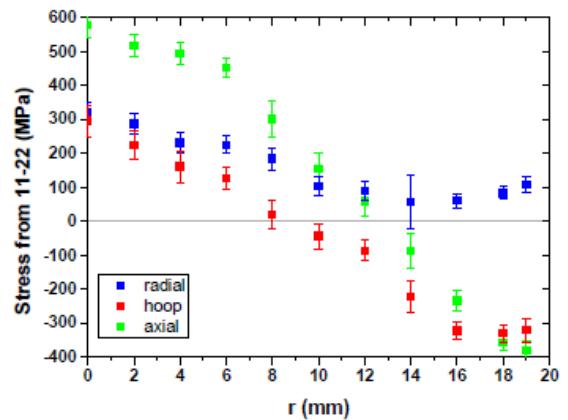
with neutrons

Experimental study and simulation of stress genesis during titanium alloys quench: phase transformation effects ?

Ti17 alloy (without phase transformation)



Ti17 alloy (with phase transformation)



Higher Stress : phase transformations effects ?

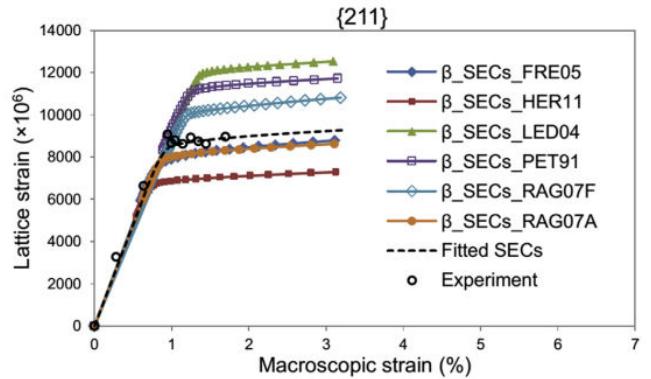
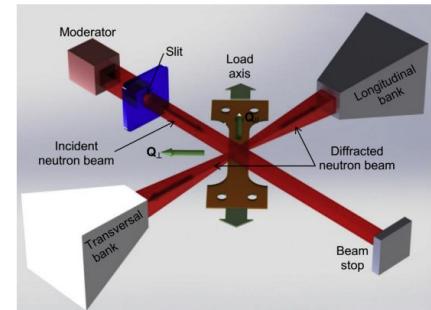
D. Maréchal et al., colloque GFAC 2016

## Internal stress determination

with neutrons

### in-situ experiments

neutron setup → large sample environments



Hounkpati et al. Acta Materialia 109 (2016) 341

## Stress determination

Laboratory, synchrotrons, neutrons

	Laboratory	Synchrotron	Neutrons
residual stress	OK	OK	OK
internal stress	variable	OK	OK
multiple techniques	OK	OK	OK
flexibility	OK	OK	OK
time consuming	measurement	preparation data analysis	preparation data analysis
diffraction mode	reflection	reflection / transmission / small angles / ...	transmission / small angles
energy	limited by tubes	no limit	limited
analyzed volume	surface / $\mu\text{m}^3$	$\mu\text{m}^3$ to $\text{mm}^3$	$\text{mm}^3$ to $\text{cm}^3$
stress determination	biaxial	full tensor	full tensor

Laboratory, synchrotron and neutrons are complementary.

Large scale facilities are open for users !

## Stress determination

Laboratory, synchrotrons, neutrons



T. Buslaps, V. Honkimaki, M Di  
Michel ID15

J.S. Micha, O. Roback, O. Ulrich  
BM32

N. Boubet, N. Blanc BM02

D. Thiaudiére, C. Mocuta

N. Tamura

R. Wimporay



P.O. Renault, E. Le Bourhis, P.  
Godeau, R. Guillou, S. Diaziri, B.  
Girault

B. Panicaud

J.L. Grosseau-Poussard, F.  
Rakotovao, M. Guérain

B. Malard

F. Lefebvre, E. Wasniewski

P. Boulet, C. Rampelberg, B.  
Denand, L. Vautrot, D. Maréchal, J.  
Teixeira, S. Denis

